

Supporting Information

Intrinsic internal standard substrate of Au@PS-b-P4VP for rapid quantification by surface enhanced Raman scattering

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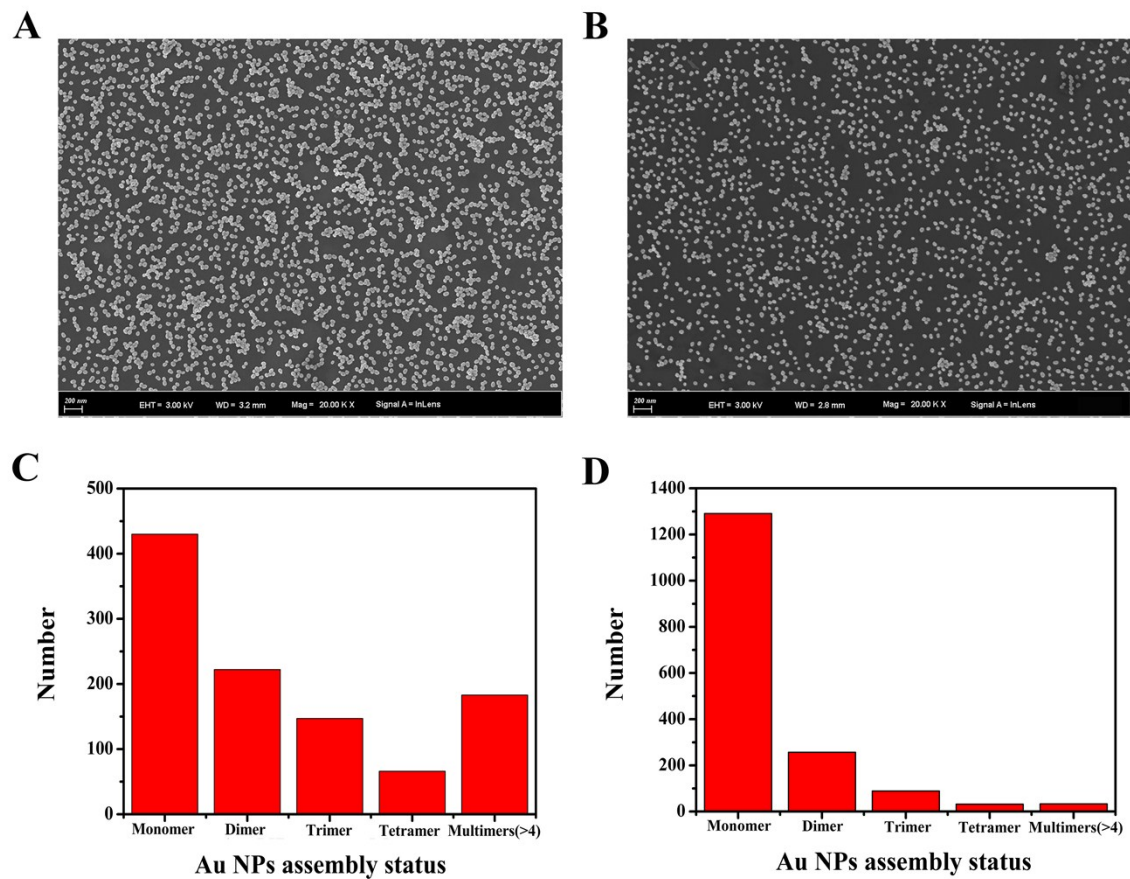


Fig. S1 (A) SEM images of Au@PS-b-P4VP SERS substrate prepared under optimized immersion time in Au colloid. (B) SEM images of substrate obtained with treatment of cross-linking. The scale bars all represent 200 nm. (C and D) The statistic distribution of Au NPs aggregation status for condition of (A) and (B), respectively.

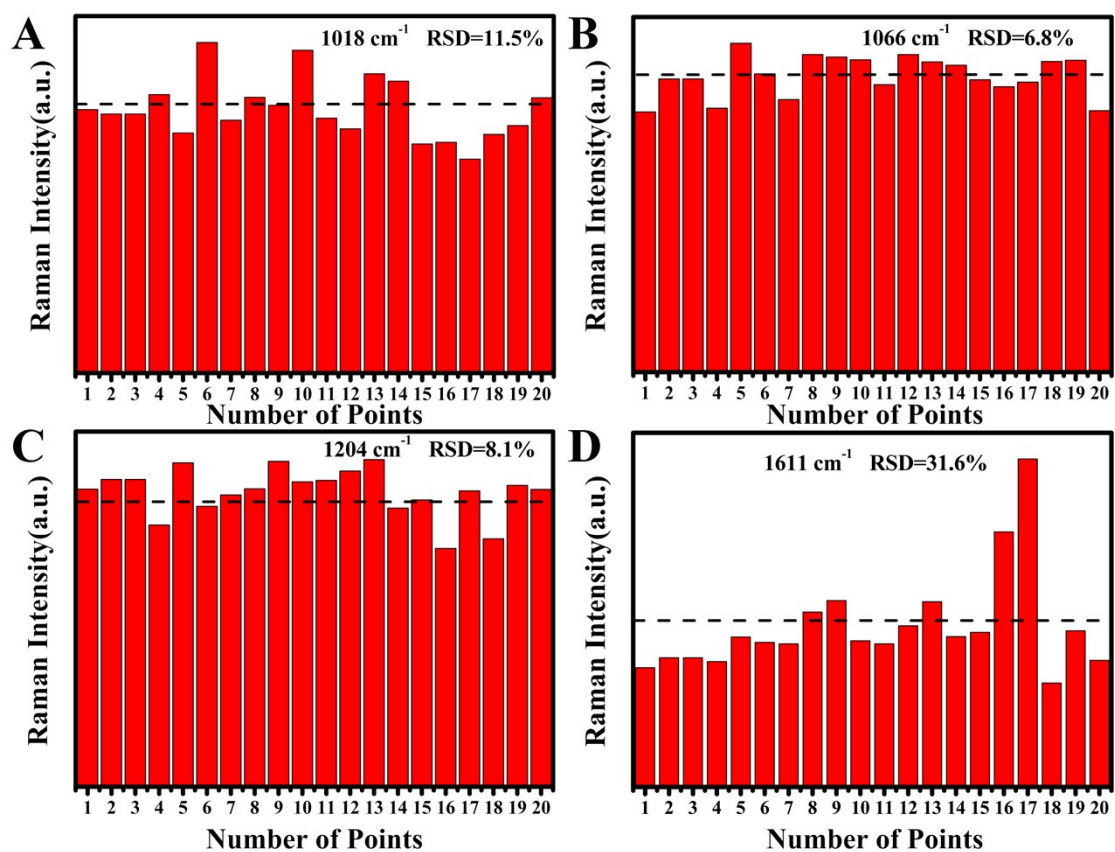


Fig. S2 The fluctuation of SERS intensities of Au@PS-b-P4VP substrate from 20 randomly selected spots on one substrate. RSDs of signal fluctuation at 1018 (A), 1066 (B), 1204 (C) and 1611 (D) cm^{-1} were 11.5%, 6.8%, 8.1% and 31.6%, respectively.